Application/Control No. 10/706,097 Applicant(s)/Patent Under Reexamination PAN ET AL. Examiner HOAN C. NGUYEN Applicant(s)/Patent Under Reexamination PAN ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2004/0010196	01-2004	Wang et al.	600/476
*	В	US-2003/0128150	07-2003	McMakin et al.	342/22
*	С	US-2003/0035610	02-2003	Keys et al.	385/16
*	D	US-5,184,233	02-1993	Lim et al.	349/166
	Е	US-			
	F	US-			
	G	US-			,
	Η	US-			
	I	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification	
	N					,	
	0						
	Р						
	Q						
	R						
	S						
	Т						

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Masaki Tanaka et al. "Milimeter-WaveTransmmision Properties of Nematic LC cells with a grating-pattern Electrode Structure", Japanese Journal of Applied Physics, Part 1, Vol. 39, , Number 11, pp. 6393-6396.
	V	Lim K. C. et al., "Liquid cyrstal milimeter wave electronic phase shifter", Applied Physics Letters 62 (10), 8 March 1993.
	w	
	x	

A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.